## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s):	Lu et al.	)	Express Mail No. EV322440308US
Serial No.:	TBD	)	
Filed:	herewith	)	
E. METH	OD OF CENED ATDIC AND	)	
	OD OF GENERATING AN STUCK-AT FAULT AND	)	
	N DELAY FAULT	)	
	D SCAN TEST PATTERN FOR	)	
AN INTEGR.	ATED CIRCUIT DESIGN	)	
Group Art Un	it: TBD	)	
Examiner:	TBD		

## **INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Sir:

In accordance with 37 C.F.R. § 1.56, the references listed on the attached Form PTO-1449 are being brought to the attention of the Examiner for consideration in connection with the examination of the above-identified patent application. The Form PTO-1449 includes one (1) reference in total, listed as item AA.

This Information Disclosure Statement (IDS) is filed herewith the above-identified application, within three months of the filing date of the application, and before the mailing date of a first Office Action on the merits, and therefore, the IDS is properly submitted pursuant to 37 C.F.R. § 1.97(b), and therefore it is believed that no fee is due for the filing of this IDS. However, if a fee is required, the Commissioner is authorized to charge the unpaid amount to Deposit Account No.12-2252.

In accordance with the duty of disclosure imposed by 37 C.F.R. § 1.56 to inform the Patent Office of all references known by Applicants or Applicants' representative that may be material to the examination of the subject application, Applicants' representative hereby

Attorney Docket No. 03-1978 81641

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provides this Information Disclosure Statement prepared in accordance with 37 C.F.R. §§ 1.97-1.98 and includes Form PTO-1449.

Copies of the items listed on Form PTO-1449 are provided pursuant to C.F.R. § 1.98(a)(2).

The items listed on the attached Form PTO-1449 are in the English language. Therefore, no further explanation of the listed items is required. See 37 CFR 1.98(a)(3)(ii).

Applicants respectfully request that the Examiner review the listed references and that they be made of record in the file history of the above-captioned application.

Although these documents are being made known to the Patent and Trademark Office in compliance with Applicant's duty of disclosure, such disclosure is not to be construed as an admission by Applicants or Applicants' representative that the reference is material to patentability or effective as prior art against the subject application.

The Commissioner is hereby authorized to charge any additional fees which may be required in this application under 37 C.F.R. §§1.16-1.17 during its entire pendency, or credit any overpayment, to Deposit Account No. 12-2252. Should no proper payment be enclosed herewith, as by a check being in the wrong amount, unsigned, post-dated, otherwise improper or informal or even entirely missing, the Commissioner is authorized to charge the unpaid amount to Deposit Account No. 12-2252.

Dated: December 3, 2003

Whitesell

Registration No. 38,657

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Form PTO-1449 (Modified)	Application No.	TBD		
INFORMATION DISCLOSURE	Filing Date	December 3, 2003		
CITATION IN AN APPLICATION	First Named Inventor	LU, Cam L.		
	Group Art Unit	TBD		
	Examiner Name	TBD		
Sheet 1 of 1	Attorney Docket No.	03-1978 81641		

U.S. PATENT DOCUMENTS									
EXAMINER INITIALS*	NO.	COPY NOT ENCLOSE D PER 37	U.S. PATENT DOCUMENT		NAME OF INVENTOR OR APPLICANT	DATE OF ISSUANCE OR PUBLICATIO	CLASS	SUB CLASS	FILING DATE (if appropriate)
	CI DP CI 1.5	CFR § 1.98(d)	PATENT, PUB., OR APP. NO.	KIND CODE (if known)		N (MM-DD- YYYY)		SUB	
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OTHER DOCUMENTS NON PATENT LITERATURE DOCUMENTS				
EXAMINE R INITIALS*	CITE NO.	COPY NOT ENCLOSED PER 37 CFR § 1.98(d)	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	
	AA		BENWARE, B.R.; Effectiveness Comparisons of Outlier Screening Methods for Frequency Dependent Defects on Complex ASICs; LSI Logic Corporation and IC Design & Test Lab, Portland State University.	
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Examiner Signature		Date Considered		
*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 8609. Draw line through citation if not in				

\*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP §609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.